



#### Very Low Power 4-Output PCIe Clock Generator With On-chip Termination

#### **Features**

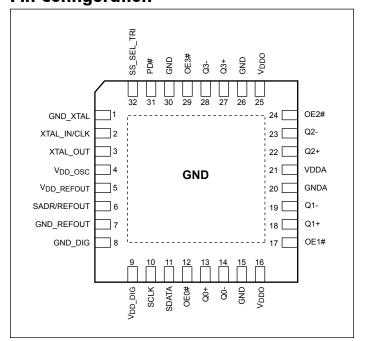
- → 1.8V supply voltage
- → Crystal/CMOS input: 25 MHz
- → 4 differential low power HCSL outputs with on-chip termination
- → Individual output enable
- → Reference CMOS output
- → Programmable Slew rate and output amplitute for each output
- → Differential outputs blocked until PLL is locked
- → Selectable 0%, -0.25% or -0.5% spread on differential outputs
- → Strapping pins or SMBus for configuration;
- → 3.3V tolerant SMBus interface support
- → Very low jitter outputs
  - → Differential cycle-to-cycle jitter <50ps
  - → Differential output-to-output skew <50ps
  - → PCIe Gen1/Gen2/Gen3/ Gen4 compliant
  - → CMOS REFOUT phase jitter is < 1.5ps RMS
- → Packaging (Pb-free & Green): 32-lead 5×5mm TQFN

### **Description**

The PI6CG18401 is an 4-output very low power PCIe Gen1/Gen2/Gen3/ Gen4 clock generator. It uses 25MHz crystal or CMOS reference as an input to generate the 100MHz low power differential HCSL outputs with on-chip terminations. The on-chip termination can save 16 external resistors and make layout easier. An additional buffered reference output is provided to serve as a low noise reference for other circuitry.

It uses Diodes proprietary PLL design to achieve very low jitter that meets PCIe Gen1/Gen2/Gen3 requirements. It also provides various options such as different slew rate and amplitude through strapping pins or SMBUS so that users can configure the device easily to get the optimized performance for their individual boards. The device also supports selectable spread-spectrum options to reduce EMI for various applications.

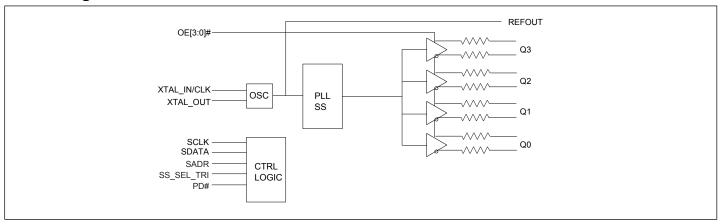
### **Pin Configuration**







# **Block Diagram**



## **Pin Description**

Pin #	Pin Name	Type		Description
1	GND_XTAL	Power		Ground for oscillator circuit
2	XTAL_IN/CLK	Input		Crystal input or CMOS reference input
3	XTAL_OUT	Output		Crystal output
4	V <sub>DD</sub> _OSC	Power		Power supply for oscillator circuitry, nominal 1.8V
5	V <sub>DD</sub> _REFOUT	Power		Power supply for buffered CMOS output
6	SADR/REFOUT	Input/ Output	CMOS	Latch to select SMBus Address or 1.8V LVCMOS REFOUT. This pin has internal pull-down.
7	GND_REFOUT	Power		Ground for REFOUT
8	GND_DIG	Power		Ground for digital circuitry
9	V <sub>DD</sub> _DIG	Power		Power supply for digital circuitry, nominal 1.8V
10	SCLK	Input	CMOS	SMBUS clock input, 3.3V tolerant
11	SDATA	Input/ Output	CMOS	SMBUS Data line, 3.3V tolerant
12	OE0#	Input	CMOS	Active low input for enabling Q0 pair. This pin has an internal pull-down. $1 = $ disable outputs, $0 = $ enable outputs
13	Q0+	Output	HCSL	Differential true clock output
14	Q0-	Output	HCSL	Differential complementary clock output
15, 26, 30	GND	Power		Ground
16, 25	V <sub>DDO</sub>	Power		Power supply for differential outputs
17	OE1#	Input	CMOS	Active low input for enabling Q1 pair. This pin has an internal pull-down. 1 =disable outputs, 0 = enable outputs
18	Q1+	Output	HCSL	Differential true clock output
19	Q1-	Output	HCSL	Differential complementary clock output
20	GNDA	Power		Ground for analog circuitry

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## Pin Description (cont.)

Pin #	Pin Name	Type		Description
21	$V_{\mathrm{DDA}}$	Power		Power supply for analog circuitry
22	Q2+	Output	HCSL	Differential true clock output
23	Q2-	Output	HCSL	Differential complementary clock output
24	OE2#	Input	CMOS	Active low input for enabling Q2 pair. This pin has an internal pulldown. 1 = disable outputs, 0 = enable outputs
27	Q3+	Output	HCSL	Differential true clock output
28	Q3-	Output	HCSL	Differential complementary clock output
29	OE3#	Input	CMOS	Active low input for enabling Q3 pair. This pin has an internal pull-down. 1 =disable outputs, 0 = enable outputs
				Input notifies device to sample latched inputs and start up on first high
31	PD# Inp		CMOS	assertion. Low enters Power Down Mode, subsequent high assertions exit Power Down Mode. This pin has internal pull-up resistor.
22	CC CEI TDI	Input	Tri-level	Latched select input to select spread spectrum amount at initial power up
32	32 SS_SEL_TRI		111-level	1 = -0.5% spread, $M = -0.25%$ , $0 = Spread Off$

## **SMBus Address Selection Table**

	SADR	Address	+Read/Write Bit
State of SADB on first application of DD#	0	1101000	X
State of SADR on first application of PD#	1	1101010	X

# **Power Management Table**

PD#	SMBus OE bit	OEn#	Qn+	Qn-	REFOUT
0	X	X	Low	Low	HiZ
1	1	0	Running	Running	Running
1	1	1	Low	Low	Low
1	0	X	Low	Low	Low





# **Maximum Ratings**

(Above which useful life may be impaired. For user guidelines, not tested.)

Storage Temperature65°C to +150	0°C
Supply Voltage to Ground Potential, VDDxx0.5V to +2	
Input Voltage0.5V to VDD+0.5V, not exceed 2	.5V
SMBus, Input High Voltage	.6V
ESD Protection (HBM)200	0 V
Max Junction Temperature+125°C	

**Note:** Stresses greater than those listed under MAXIMUM RATINGS may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect reliability.

## **Operating Conditions**

Temperature = T<sub>A</sub>; Supply voltages per normal operation conditions; See test circuits for the load conditions

Symbol	Parameters	Conditions	Min.	Тур.	Max.	Units
V <sub>DD</sub> , V <sub>DDA</sub> , V <sub>DD</sub> OSC, V <sub>DD</sub> RE- FOUT, V <sub>DD</sub> DIG	Power Supply Voltage		1.7	1.8	1.9	V
$V_{\mathrm{DDO}}$	Output Power Supply Voltage		1.7	1.8	1.9	V
I <sub>DDA</sub>	Analog Power Supply Current	All outputs active @100MHz		6	9	mA
$I_{\mathrm{DD}}$	Power Supply Current	All $V_{DD}$ , except $V_{DDA}$ and $V_{DDO}$ , All outputs active @100MHz		4	6	mA
$I_{\mathrm{DDO}}$	Power Supply Current for Outputs	All outputs active @100MHz		21	25	mA
I <sub>DDA_WL</sub>	Analog Power Supply Wake-on- LAN <sup>1</sup> Current	Q outputs off, REF output running		0.4	1	mA
I <sub>DD_WL</sub>	Power Supply Wake-on-LAN <sup>1</sup> Current	All V <sub>DD</sub> , except V <sub>DDA</sub> and V <sub>DDO</sub> , Q outputs off, REF output running		1	2	mA
I <sub>DDO_WL</sub>	Power Supply Wake-on-LAN <sup>1</sup> Current for Outputs	Q outputs off, REF output running		0.04	0.1	mA
I <sub>DDA_PD</sub>	Analog Power Supply Power Down <sup>2</sup> Current	All outputs off		0.4	1	mA
I <sub>DD_PD</sub>	Power Supply Power Down <sup>2</sup> Current	All outputs off		0.6	1	mA
I <sub>DDO_PD</sub>	Power Supply Current Power Down <sup>2</sup> for Outputs	All outputs off		0.0005	0.1	mA
T <sub>A</sub>	Ambient Temperature	Industrial grade	-40		85	°C

#### Note:

- 1. Wake-on-LAN mode: PD# = '0' Byte 3, bit 5 = '1'
- 2. Power down mode: PD# = '0' Byte 3, bit 5 = '0'





# **Input Electrical Characteristics**

Symbol	Parameters	Conditions	Min.	Тур.	Max.	Units
R <sub>pu</sub>	Internal pull up resistance			120		ΚΩ
R <sub>dn</sub>	Internal pull down resistance			120		ΚΩ
$C_{XTAL}$	Internal capacitance on X_IN and X_OUT pins			5		pF
L <sub>PIN</sub>	Pin inductance				7	nН

## **Crystal Characteristic**

Parameters	Description	Min.	Тур	Max.	Units
OSCmode	Mode of Oscillation	F	undamenta		
FREQ	Frequency		25		MHz
ESR <sup>1</sup>	Equivalent Series Resistance			50	Ω
Cload	Load Capacitance		8		pF
Cshunt	Shunt Capacitance			7	pF
	Drive Level			300	uW

#### Note:

### **SMBus Electrical Characteristics**

Temperature = T<sub>A</sub>; Supply voltages per normal operation conditions; See test circuits for the load conditions

Symbol	Parameters	Conditions	Min.	Тур.	Max.	Units
V <sub>DDSMB</sub>	Nominal bus voltage		1.7		3.6	V
		SMBus, $V_{DDSMB} = 3.3V$	2.1		3.6	
	SMBus Input High Voltage	SMBus, $V_{DDSMB} < 3.3V$	0.65 V <sub>DDSMB</sub>			V
7.7	SMBus Input Low Voltage	SMBus, $V_{DDSMB} = 3.3V$			0.6	V
V <sub>ILSMB</sub>		SMBus, V <sub>DDSMB</sub> < 3.3V			0.6	
I <sub>SMBSINK</sub>	SMBus sink current	SMBus, at V <sub>OLSMB</sub>	4			mA
V <sub>OLSMB</sub>	SMBus Output Low Voltage	SMBus, at I <sub>SMBSINK</sub>			0.4	V
f <sub>MAXSMB</sub>	SMBus operating frequency	Maximum frequency			400	kHz
t <sub>RMSB</sub>	SMBus rise time	(Max V <sub>IL</sub> - 0.15) to (Min V <sub>IH</sub> + 0.15)			1000	ns
t <sub>FMSB</sub>	SMBus fall time	(Min $V_{IH}$ + 0.15) to (Max $V_{IL}$ - 0.15)		·	300	ns

## **Spread Spectrum Characteristic**

Temperature = T<sub>A</sub>; Supply voltages per normal operation conditions; See test circuits for the load conditions

Symbol	Parameters	Conditions	Min.	Тур.	Max.	Units
$f_{MOD}$	SS Modulation Frequency	Triangular modulation	30	31.6	33	kHz

<sup>1.</sup> ESR value is dependent upon frequency of oscillation





### **LVCMOS DC Electrical Characteristics**

Temperature = T<sub>A</sub>; Supply voltages per normal operation conditions; See test circuits for the load conditions

Symbol	Parameters	Conditions	Min.	Тур.	Max.	Units
V <sub>IH</sub>	Input High Voltage	Single-ended inputs, except SMBus	0.75 V <sub>DD</sub>		V <sub>DD</sub> +0.3	V
V <sub>IM</sub>	Input Mid Voltage	SS_SEL_TRI	$0.4 V_{ m DD}$	$0.5V_{ m DD}$	$0.6 V_{ m DD}$	V
$V_{\rm IL}$	Input Low Voltage	Single-ended inputs, except SMBus	-0.3		0.25 V <sub>DD</sub>	V
$I_{IH}$	Input High Current	Single-ended inputs, $V_{IN} = V_{DD}$			20	μΑ
I <sub>IL</sub>	Input Low Current	Single-ended inputs, $V_{IN} = 0V$	-20			μА
$I_{IH}$	Input High Current	Single-ended inputs with pull up / pull down resistor, $V_{\rm IN} = V_{\rm DD}$			220	μА
$I_{\mathrm{IL}}$	Input Low Current	Single-ended inputs with pull up / pull down resistor, $V_{\rm IN} = 0 V$	-220			μА
V <sub>OH</sub>	Output High Voltage	REFOUT, except SMBus; I <sub>OH</sub> = -2mA	V <sub>DD</sub> -0.45			V
V <sub>OL</sub>	Output Low Voltage	REFOUT, except SMBus; I <sub>OH</sub> = 2mA			0.45	V
R <sub>OUT</sub>	CMOS Output impedance			20		Ω
C <sub>IN</sub>	Input Capacitance		1.5		5	pF

### **LVCMOS AC Characteristics**

Temperature = T<sub>A</sub>; Supply voltages per normal operation conditions; See test circuits for the load conditions

Symbol	Parameters	Conditions	Min.	Тур.	Max.	Units
f <sub>INPUT</sub>	Input Frequency	XTAL_IN/CLK	23	25	27	MHz
t <sub>RIN</sub>	Input rise time	Single-ended inputs			5	ns
t <sub>FIN</sub>	Input fall time	Single-ended inputs			5	ns
t <sub>STAB</sub>	Clock stablization	From Power-Up and after input clock stabilization or de-assertion of PD# to 1st clock		0.6	1.8	ms
t <sub>OELAT</sub>	Output enable latency	Q start after OE# assertion Q stop after OE# deassertion	1		3	clocks
t <sub>PDLAT</sub>	PD# de-assertion	Differential outputs enable after PD# deassertion		20	300	us
t <sub>PERIOD</sub>	REFOUT clock period	REFOUT, assume input is at 25MHz		40		ns
f <sub>ACC</sub>	REFOUT frequency accuracy 1	REFOUT, long term accuracy to input		0		ppm
		Byte 3 = 1F, 20% to 80% of V <sub>DDREF</sub>	0.6	1	1.8	V/ns
	DEPOLIT 1 4 1	Byte 3 = 5F, 20% to 80% of V <sub>DDREF</sub>	0.75	1.6	2.5	V/ns
t <sub>SLEW</sub>	REFOUT slew rate <sup>1</sup>	Byte 3 = 9F, 20% to 80% of V <sub>DDREF</sub>	0.85	2.0	3.0	V/ns
		Byte 3 = DF, 20% to 80% of V <sub>DDREF</sub>	1.0	2.1	3.1	V/ns
$t_{DC}$	REFOUT Duty Cycle <sup>1</sup>	$V_T = V_{\rm DD}$ /2 V, driven by a Xtal	45	50	55	%





### **LVCMOS AC Characteristics (Cont.)**

Symbol	Parameters	Condition	Min.	Тур.	Max.	Units
t <sub>DCDIS</sub>	REFOUT Duty Cycle Distortion	$V_T = V_{DD} / 2$ V, driven by an external source	0	2	4	%
t <sub>JITCC</sub>	REFOUT cycle-cycle jitter	$V_T = V_{DD} / 2 V$ , driven by a Xtal		70	130	ps
t <sub>JITPH</sub>	REFOUT phase jitter	12kHz to 5MHz, RMS, driven by a Xtal		0.2	0.5	ps
4	Naise flagg	1kHz offset, driven by a Xtal		-130	-105	dBc
t <sub>JITN</sub>	Noise floor	10kHz offset to Nyquist, driven by a Xtal		-140	-120	dBc

#### Note:

### **HCSL Output Characteristics**

Temperature = T<sub>A</sub>; Supply voltages per normal operation conditions; See test circuits for the load conditions

Symbol	Parameters	Condition	Min.	Тур.	Max.	Units
V <sub>OH</sub>	Output Voltage High <sup>1</sup>	Statistical measurement on single-ended	660	784	850	mV
V <sub>OL</sub>	Output Voltage Low <sup>1</sup>	signal using oscilloscope math function	-150		150	mV
V <sub>OMAX</sub>	Output Voltage Maximum <sup>1</sup>	Measurement on single ended signal using		816	1150	mV
V <sub>OMIN</sub>	Output Voltage Minimum <sup>1</sup>	absolute value	-300	-15		mV
Voswing	Output Swing Voltage <sup>1,2,3</sup>	Scope averaging off	300	1551		mV
V <sub>OC</sub>	Output Cross Voltage 1,2,4		250	400	550	mV
DV <sub>OC</sub>	V <sub>OC</sub> Magnitude Change <sup>1,2,5</sup>			14	140	mV

#### Note:

- 1. At default SMBUS amplitude settings
- 2. Guaranteed by design and characterization, not 100% tested in production
- 3. Measured from differential waveform
- 4. This one is defined as voltage where Q+ = Q- measured on a component test board and only applied to the differential rising edge
- 5. The total variation of all Vcross measurements in any particular system. This is a subset of Vcross\_min/max allowed.

### **HCSL Output AC Characteristics**

Temperature = T<sub>A</sub>; Supply voltages per normal operation conditions; See test circuits for the load conditions

Symbol	Parameters	Condition	Min.	Тур.	Max.	Units
f <sub>OUT</sub>	Output Frequency			100		MHz
4	Slew rate <sup>1,2,3</sup>	Scope averaging on fast setting	2	3.1	4.4	V/ns
$t_{RF}$	Siew rate	Scope averaging on slow setting	1.1	2.0	3.0	V/ns
Dt <sub>RF</sub>	Slew rate matching <sup>1,2,4</sup>	Scope averaging on		3		%
$t_{DC}$	Duty Cycle <sup>1,2</sup>	Measured differentially, PLL Mode	45	50	55	%
t <sub>SKEW</sub>	Output Skew <sup>1,2</sup>	Averaging on, $V_T = 50\%$		34	50	ps
tj <sub>c-c</sub>	Cycle to cycle jitter <sup>1,2</sup>			14	50	ps
t <sub>STARTUP</sub>	Start up time				10	ms
t <sub>LOCK</sub>	PLL lock time				20	ms

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<sup>1.</sup> Guaranteed by design and characterization, not 100% tested in production





### **HCSL Output AC Characteristics (continued)**

Symbol	Parameters	Condition	Min.	Тур.	Max.	Units
		PCIe Gen 1	20	25	86	ps
		PCIe Gen 2 Low Band, 10kHz < f < 1.5MHz	0.8	0.9	3.0	ps
tjphase	Integrated phase jitter (RMS)	PCIe Gen 2 High Band, 1.5MHz < f < Nyquist (50MHz)	1.5	1.6	3.1	ps
GPHASE	1,5,6	PCIe Gen 3 Common Clock Architecture (PLL BW of 2-4 or 2-5MHz, CDR =10MHz)	0.4	0.5	1.0	ps
		PCIe Gen 3 Separate Reference No Spread (PLL BW of 2-4 or 2-5MHz, CDR =10MHz)	0.4	0.5	0.7	ps
		PCIe Gen 4 (PLL BW of 2-4 or 2-5MHz, CDR =10MHz)	0.3	0.37	0.5	ps

#### Note:

- 1. Guaranteed by design and characterization, not 100% tested in production
- 2. Measured from differential waveform
- $3. \ Slew\ rate\ is\ measured\ through\ the\ Vswing\ voltage\ range\ centered\ around\ differential\ 0V,\ within\ +/-150mV\ window$
- 4. It is measured using a  $\pm$ 7-75mV window centered on the average cross point
- 5. See http://www.pcisig.com for complete specs
- 6. Sample size of at least 100k cycles. This can be extrapolated to 108ps pk-pk @ 1M cycles for a BER of  $10^{-12}$

# Differential Output Clock Periods - Spread Spectrum Disabled <sup>1, 2</sup>

			Meas	surement Wir	ndow			
Center	1 clock	1 us	0.1 s	0.1 s	0.1 s	1 us	1 clock	
Freq. MHz	-c2c jitter AbsPer Min	- SSC Short-term Avg. Min	-ppm Long- term Avg. min	0 ppm Period Nominal	+ppm Long-term Avg. max	+ SSC Short-term Avg. Max	-c2c jitter AbsPer Max	Units
100.00	9.94900		9.99900	10.00000	10.00100		10.05100	ns

# Differential Output Clock Periods - Spread Spectrum Enabled <sup>1, 2</sup>

			Meas	surement Wir	ndow			
Center	1 clock	1 us	0.1 s	0.1 s	0.1 s	1 us	1 clock	
Freq. MHz	-c2c jitter AbsPer Min	- SSC Short-term Avg. Min	-ppm Long- term Avg. min	0 ppm Period Nominal	+ppm Long-term Avg. max	+ SSC Short-term Avg. Max	-c2c jitter AbsPer Max	Units
99.75	9.94906	9.99906	10.02406	10.02506	10.02607	10.05107	10.10107	ns

#### Note:

- 1. Guaranteed by design and characterization, not 100% tested in production
- 2. All long term accuracy and clock period specifications are guaranteed assuming REF is trimmed to 25.00MHz





### **SMBus Serial Data Interface**

PI6CG18401 is a slave only device that supports block read and block write protocol using a single 7-bit address and read/write bit as shown below.

Read and write block transfers can be stopped after any complete byte transfer.

### **Address Assignment**

A6	A5	A4	A3	A2	A1	A0	R/W
1	1	0	1	0	SADR	0	1/0

Note: SMBus address is latched on SADR pin

#### **How to Write**

1 bit	7 bits	1 bit	1 bit	8 bits	1 bit	8 bits	1 bit	8 bits	1 bit	8 bits	1 bit	1 bit
Start bit	Add.	W(0)	Ack	Beginning Byte loca- tion = N	Ack	Data Byte count = X	Ack	Beginning Data Byte (N)	Ack	 Data Byte (N+X-1)	Ack	Stop bit

### **How to Read**

1 bit	7 bits	1 bit	1 bit	8 bits	1 bit	1 bit	7 bits	1 bit	1 bit	8 bits	1 bit	8 bits	1 bit
Start bit	Address	W(0)	Ack	Beginning Byte location = N	Ack	Repeat Start bit	Address	R(1)	Ack	Data Byte count = X	Ack	Beginning Data Byte (N)	Ack

8 bits	1 bit	1 bit
Data Byte	NAck	Stop bit
(N+X-1)	IVACK	Stop bit





# Byte 0: Output Enable Register <sup>1</sup>

Bit	<b>Control Function</b>	Description	Туре	Power Up Condition	0	1
7	Reserved			1		
6	Reserved			1		
5	Reserved			1		
4	Reserved			1		
3	Q3_OE	Q3 output enable	RW	1	Low/Low	Enabled
2	Q2_OE	Q2 output enable	RW	1	Low/Low	Enabled
1	Q1_OE	Q1 output enable	RW	1	Low/Low	Enabled
0	Q0_OE	Q0 output enable	RW	1	Low/Low	Enabled

#### Note:

# Byte 1: SS Readback and Control Register

Bit	Control Function	Description	Туре	Power Up Condition	0	1
7	SSENRB1	SS Enable Readback Bit1	R	Latch	'00' for SS_SEL_	TRI = '0',
6	SSENRB0	SS Enable Readback Bit0	R	Latch	'01' for SS_SEL_ '11' for SS_SEL_	,
5	SSEN_SWCTR	Enable SW control of SS	RW	0	Values in B1[7:6] control SS amount	Values in B1[4:3] control SS amount
4	SSENSW1	SS enable SW control Bit1	RW <sup>1</sup>	0	'00' = SS off, '01	' = -0.25% SS,
3	SSENSW0	SS enable SW control Bit0	RW <sup>1</sup>	0	'10' = Reserved,	'11' = -0.5% SS
2	Reserved			1		
1	Amplitude1	Control output applitude	RW	1	'00' = 0.6V, '01' =	= 0.7V, '10' =
0	Amplitude0	Control output applitude	RW	0	0.8V, '11' = 0.9V	

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#### Note:

1. B1[5] must be set to a 1 for these bits to have any effect on the part.

 $<sup>1. \</sup> A \ low \ on \ these \ bits \ will \ override \ the \ OE\# \ pins \ and \ force \ the \ differential \ outputs \ to \ Low/Low \ states$ 





# Byte 2: Differential Output Slew Rate Control Register

Bit	Control Function	Description	Туре	Power Up Condition	0	1
7	Reserved			1		
6	Reserved			1		
5	Reserved			1		
4	Reserved			1		
3	SLEWRATECTR_Q3	Control slew rate of Q3	RW	1	Slow setting	Fast setting
2	SLEWRATECTR_Q2	Control slew rate of Q2	RW	1	Slow setting	Fast setting
1	SLEWRATECTR_Q1	Control slew rate of Q1	RW	1	Slow setting	Fast setting
0	SLEWRATECTR_Q0	Control slew rate of Q0	RW	1	Slow setting	Fast setting

# **Byte 3: REF Control Register**

Bit	Control Function	Description	Туре	Power Up Condition	0	1
7	REFSLEWRATE	Classicate as a track from DEE	RW	0	'00' = 0.9V/ns '0	1' = 1.3V/ns,
6	REFSLEWRATE	Slew rate control for REF	RW	1	'10' = 1.6V/ns, '1	1' = 1.8V/ns
5	REF_PDSTATE	Wake-on-Lan enable for REF	RW	0	REF = 'Low'	REF = run- ning
4	REF_OE	Output enable for REF	RW	1	REF = "Low'	REF = run- ning
3	Reserved			1		
2	Reserved			1		
1	Reserved			1		
0	Reserved			1		

# **Byte 4: Reserved**

Bit	Control Function	Description	Туре	Power Up Condition	0	1
7:0	Reserved					

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# Byte 5: Revision and Vendor ID Register

Bit	Control Function	Description	Туре	Power Up Condition	0	1
7	RID3		R	0	rev = 0000	
6	RID2	Revision ID	R	0		
5	RID1		R	0		
4	RID0		R	0		
3	PVID3		R	0		
2	PVID3	Wandan ID	R	0	Diodes = 0011	
1	PVID3	-	R	1		
0	PVID3		R	1		

# Byte 6: Device Type/Device ID Register

Bit	Control Function	Description	Туре	Power Up Condition	0	1
7	DTYPE1	D : 1	R	0	'00' = CG, '01' =	ZDB,
6	DTYPE0	Device type	R	0	'10' = Reserve, '11' = ZDB	
5	DID5		R	0		
4	DID4		R	0		
3	DID3	Device ID	R	0	000100 binary, 04Hex	
2	DID2	Device ID	R	1		
1	DID1		R	0		
0	DID0		R	0		

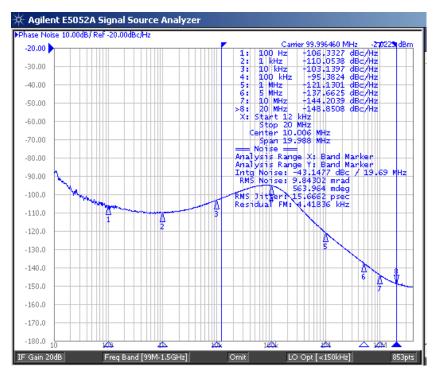
# **Byte 7: Byte Count Register**

Bit	Control Function	Description	Туре	Power Up Condition	0	1
7	Reserved			0		
6	Reserved			0		
5	Reserved			0		
4	BC4		RW	0		
3	BC3		RW	1	Writing to this register will configure how many bytes be read back, default is 8 by	
2	BC2	Byte count programming	RW	0		
1	BC1		RW	0		
0	BC0		RW	0		

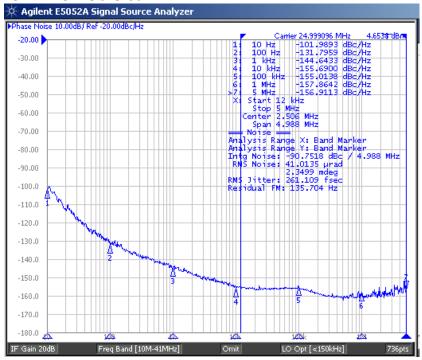




### Plots 100MHz HCSL Clock



### 25MHz CMOS Clock







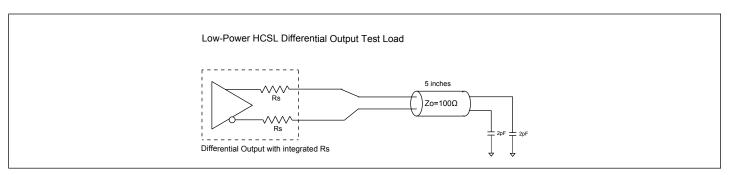


Figure 1. Low Power HCSL Test Circuit

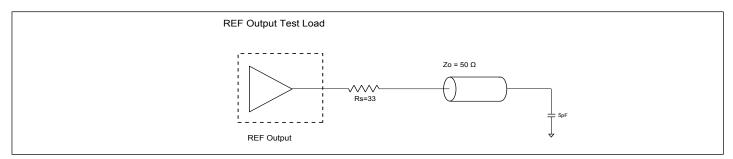


Figure 2. CMOS REF Test Circuit

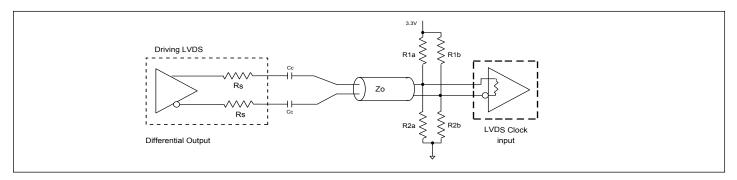


Figure 3. Differential Output driving LVDS

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## **Alternate Differential Output Terminations**

Component	Receiver with termination	Receiver without termination	Unit
$R_{1a}, R_{1b}$	10,000	140	Ω
$R_{2a}, R_{2b}$	5,600	75	Ω
C <sub>C</sub>	0.1	0.1	μF
$V_{CM}$	1.2	1.2	V





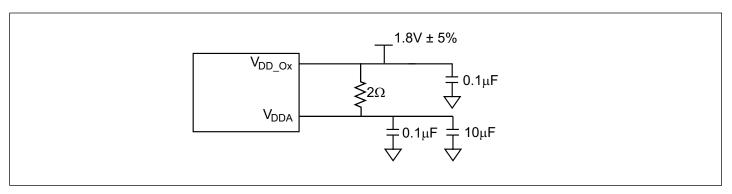


Figure 4. Power Supply Filter

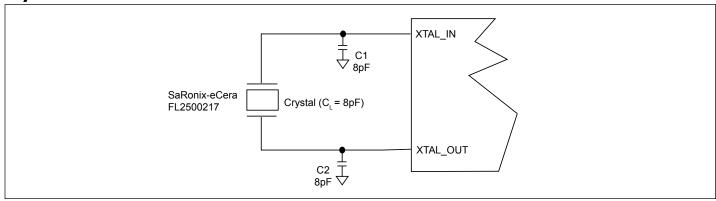




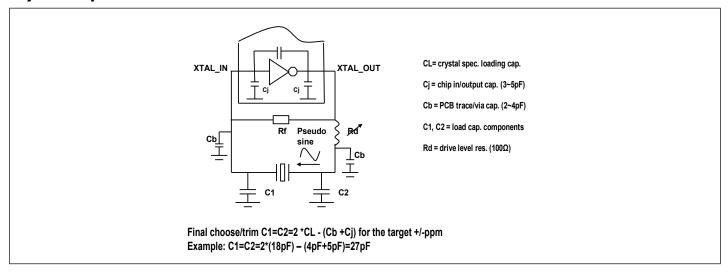
### **Crystal circuit connection**

The following diagram shows PI6CG18401 crystal circuit connection with a parallel crystal. For the CL=8pF crystal, it is suggested to use C1=8pF, C2=8pF. C1 and C2 can be adjusted to fine tune to the target ppm of crystal oscillator according to different board layouts based on the following formular in the Crystal Capacitor Calculation diagram.

### **Crystal Oscillator Circuit**



### **Crystal Capacitor Calculation**



## **Recommended Crystal Specification**

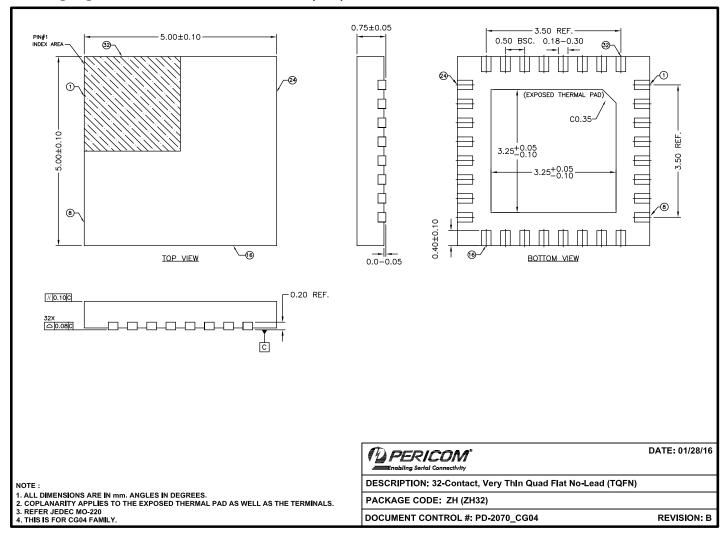
#### **Diodes recommends:**

a) FL2500217, SMD 3.2x2.5(4P), 25MHz, CL=8pF, +/-20ppm, http://www.Diodes.com/pdf/datasheets/se/FL.pdf





## Packaging Mechanical: 32-Pin TQFN (ZH)



Note: For latest package info, please check: http://www.Diodes.com/support/packaging/packaging-mechanicals-and-thermal-characteristics/

# Ordering Information<sup>(1-3)</sup>

Ordering Code	Package Code	Package Description	Operating Temperature
PI6CG18401ZHIE	ZH	32-Contact, Very Thin Quad Flat No-Lead (TQFN)	Industrial
PI6CG18401ZHIEX	ZH	32-Contact, Very Thin Quad Flat No-Lead (TQFN), Tape & Reel	Industrial

#### Notes:

- 1. Thermal characteristics can be found on the company web site at www.Diodes.com/packaging/
- 2. E = Pb-free and Green
- 3. Adding an X suffix = Tape/Reel





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